

**Notice of References Cited**

Application/Control No.

09/319,222

Applicant(s)/Patent Under  
Reexamination  
HEED ET AL.

Examiner

Dennis-Doon Chow

Art Unit

2675

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,317,399	05-1994	Satake et al.	348/571
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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